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Cleanroom Certification Measu	rements	
Standard Measurements		
1. Air velocity / Air velocity distribution		
2. Filter Airflow rate		
3. AHU Airflow rate		
4. Filter leakage test		
5. Room pressurisation	Optional Measurements	
6. Cleanliness classification	1. Containment leak test / Enclosure	re
7. Temperature and Humidity	integrity test	
	2. Parallelism - Airflow direction tes Airflow visualisation	st
	3. Recovery time	
	4. Microbiological count (Air, surfac	ces)
	5. 3 rd Party Certification	
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Cleanroom Certification: Reco	overy Time Measurement
Purpose	Requirements
To test the installations ability to eliminate airborne particles	 Cleanroom installation completed
Only performed in cleanrooms with	
turbulent airflow	 Air velocity adjustment, Airflow volume adjustment and room pressurization adjustment in the order of the maintenance group
Standards	
 VDI 2083, sheet 3 (Draft 1993) or (not and) IES-RP-CC006.2 (1994) or (not and) 	Air velocity test, Airflow volume test, Filter leakage test and room pressurization test completed
 ISO (DIS) 14644-3 (Draft 2000) or (not and) 	
■ NEBB (1996)	
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Cleanroom Certification: Tempe	rature and Relative Humidity
Purpose	Requirements
To verify of the capability of the Cleanroom air handling system to maintain the specified air temperature and relative humidity	 Cleanroom installation totally completed
	 Air velocity adjustment, Airflow volume adjustment and Room pressurization adjustment completed in the order of the maintenance group
Standards	Make up air system installed and adjusted
VDI 2083, sheet 3 (1993) or (not and)	Temperature control system installed and adjusted
IES-RP-CC006.2 (1994) or (not and)	Air velocity test, Airflow volume test,
ISO (DIS) 14644-3 or (not and)	Filter leakage test, Room pressurization test and Parallelism
■ NEBB (1996)	test completed
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